



#### COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

#### **Product Summary**

Device	BV <sub>DSS</sub>	R <sub>DS(ON)</sub>	I <sub>D</sub> T <sub>A</sub> = +25°C
N Channal	nel 20V	42mΩ @ V <sub>GS</sub> = 4.5V	4.0A
N-Channel		60mΩ @ V <sub>GS</sub> = 2.5V	3.5A
P-Channel	201/	70mΩ @ V <sub>GS</sub> = -4.5V	-3.3A
P-Grianner	-20V	100mΩ @ V <sub>GS</sub> = -2.5V	-2.8A

# Features and Benefits

- Low On-Resistance
- Low Input Capacitance
- · Fast Switching Speed
- Low Input/Output Leakage
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)

#### **Description**

This new generation MOSFET is designed to minimize the on-state resistance (R<sub>DS(ON)</sub>) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

## **Applications**

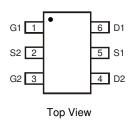
- Backlighting
- DC-DC Converters
- Power Management Functions

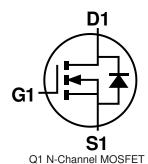
#### **Mechanical Data**

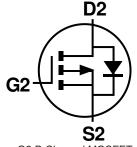
- Case: TSOT26
- Case Material: Molded Plastic, "Green" Molding Compound.
   UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals Connections: See Diagram
- Terminals: Finish Matte Tin Annealed over Copper Leadframe. Solderable per MIL-STD-202, Method 208 (3)
- Weight: 0.013 grams (Approximate)











Q2 P-Channel MOSFET

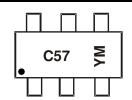
#### Ordering Information (Note 4)

Part Number	Case	Packaging
DMC2057UVT-7	TSOT26	3000 / Tape & Reel
DMC2057UVT-13	TSOT26	10000 / Tape & Reel

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
- See http://www.diodes.com/quality/lead\_free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at https://www.diodes.com/design/support/packaging/diodes-packaging/.

# **Marking Information**



C57 = Product Type Marking Code YM = Date Code Marking Y or  $\overline{Y}$  = Year (ex: F = 2018) M or M = Month (ex: 9 = September)

Date Code Key

Year	2018		2019	2020		2021	2022		2023	2024		2025
Code	F		G	Н			J		K	L		М
Month	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec
Code	1	2	3	4	5	6	7	8	9	0	N	D



#### **Maximum Ratings** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Q1 Value	Q2 Value	Unit		
Drain-Source Voltage			$V_{DSS}$	20	-20	V
Gate-Source Voltage			V <sub>GSS</sub>	±12	±8	V
Continuous Drain Current (Note 6)	Observation	T 0500		4.0	0.0	
N-Channel: V <sub>GS</sub> = 4.5V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I <sub>D</sub>	4.0 3.5	-3.3 -2.6	Α
P-Channel: V <sub>GS</sub> = -4.5V	State	1A = +/0°C		3.3	-2.0	
Maximum Continuous Body Diode Forward Current (	I <sub>S</sub>	1.2	-1.3	Α		
Pulsed Drain Current (10µs Pulse, Duty Cycle = 1%)	I <sub>DM</sub>	25	-17	Α		

### **Thermal Characteristics**

Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 5)	$T_A = +25^{\circ}C$	$P_{D}$	0.7	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	$R_{\theta JA}$	173	°C/W
Total Power Dissipation (Note 6)	T <sub>A</sub> = +25°C	P <sub>D</sub>	1.1	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	$R_{\theta JA}$	108	°C/W
Thermal Resistance, Junction to Case		$R_{ heta JC}$	37	C/VV
Operating and Storage Temperature Range		T <sub>J,</sub> T <sub>STG</sub>	-55 to +150	°C

# Electrical Characteristics Q1 N-CHANNEL(@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	20	—		V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	1.0	μΑ	$V_{DS} = 20V, V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 12V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	0.4	_	1.2	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$	
			32	42		$V_{GS} = 4.5V, I_D = 5.0A$	
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	_	40	60	mΩ	$V_{GS} = 2.5V, I_D = 4.0A$	
	, ,		50	91		V <sub>GS</sub> = 1.8V, I <sub>D</sub> = 2.0A	
Diode Forward Voltage	$V_{SD}$	_	0.7	1.2	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS (Note 8)						•	
Input Capacitance	C <sub>iss</sub>	_	416	_		V 40V V 0V	
Output Capacitance	Coss	_	44	_	pF	$V_{DS} = 10V, V_{GS} = 0V$ f = 1.0MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>	_	35	_		I = I.UVINZ	
Gate Resistance	Rg	_	2.0	_	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$ , $f = 1MHz$	
Total Gate Charge (V <sub>GS</sub> = 4.5V)	Qg	_	4.7	_			
Total Gate Charge (V <sub>GS</sub> = 10V)	Qg	_	10.5	_	nC	101/1 04	
Gate-Source Charge	Qgs	_	0.4	_	IIC	$V_{DS} = 10V$ , $I_D = 6A$	
Gate-Drain Charge	$Q_{gd}$	_	1.2	_			
Turn-On Delay Time	t <sub>D(ON)</sub>	_	2.6	_			
Turn-On Rise Time	t <sub>R</sub>	_	3.3	_	20	$V_{DS} = 10V, V_{GS} = 4.5V,$	
Turn-Off Delay Time	t <sub>D(OFF)</sub>	_	12.2	_	ns	$R_a = 6\Omega$ , $I_D = 6A$	
Turn-Off Fall Time	t <sub>F</sub>	_	3.1	_			
Reverse Recovery Time	t <sub>RR</sub>	_	8.3	_	ns	L CA di/dk 1000/	
Reverse Recovery Charge	Q <sub>RR</sub>	_	1.3		nC	$I_F = 6A$ , di/dt = 100A/ $\mu$ s	

Notes: 5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.

<sup>6.</sup> Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
7. Short duration pulse test used to minimize self-heating effect.

<sup>8.</sup> Guaranteed by design. Not subject to production testing.



### Electrical Characteristics Q2 P-CHANNEL (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition		
OFF CHARACTERISTICS (Note 7)								
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-20	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>			-1.0	μΑ	$V_{DS} = -20V, V_{GS} = 0V$		
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 8V, V_{DS} = 0V$		
ON CHARACTERISTICS (Note 7)								
Gate Threshold Voltage	V <sub>GS(TH)</sub>	-0.4	_	-1.0	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$		
			60	70		$V_{GS} = -4.5V$ , $I_{D} = -3.5A$		
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	_	73.5	100	mΩ	$V_{GS} = -2.5V$ , $I_{D} = -3.0A$		
	, ,		113	160		$V_{GS} = -1.8V, I_D = -2.0A$		
Diode Forward Voltage	V <sub>SD</sub>	_	-0.7	-1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = -1A		
DYNAMIC CHARACTERISTICS (Note 8)								
Input Capacitance	Ciss	-	536	_				
Output Capacitance	Coss	l	78	_	рF	$V_{DS} = -10V, V_{GS} = 0V,$ f = 1.0MHz		
Reverse Transfer Capacitance	Crss	_	69	_		1 = 1.01/11/12		
Gate Resistance	$R_g$	_	32	_	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$ , $f = 1MHz$		
Total Gate Charge (V <sub>GS</sub> = -4.5V)	Qq	_	6.5	_				
Gate-Source Charge	Qgs	_	0.8	_	nC	$V_{DS} = -4V, I_{D} = -3.5A$		
Gate-Drain Charge	Q <sub>gd</sub>	_	1.3	_				
Turn-On Delay Time	t <sub>D(ON)</sub>	_	4.4	_				
Turn-On Rise Time	t <sub>R</sub>	_	15.5	_		$V_{GS} = -4.5V, V_{DS} = -4V,$		
Turn-Off Delay Time	t <sub>D(OFF)</sub>	_	38.5	_	ns	$R_g = 6\Omega$ , $R_L = 4\Omega$		
Turn-Off Fall Time	t <sub>F</sub>	_	22.2	_				
Reverse Recovery Time	t <sub>RR</sub>	_	11	_	ns	$I_F = -2.0A$ , $di/dt = -100A/\mu s$		
Reverse Recovery Charge	Q <sub>RR</sub>	_	2.6	_	nC	I <sub>F</sub> = -2.0A, di/dt = -100A/μs		

Notes:

<sup>7.</sup> Short duration pulse test used to minimize self-heating effect. 8. Guaranteed by design. Not subject to production testing.



## **Typical Characteristics - N-CHANNEL**

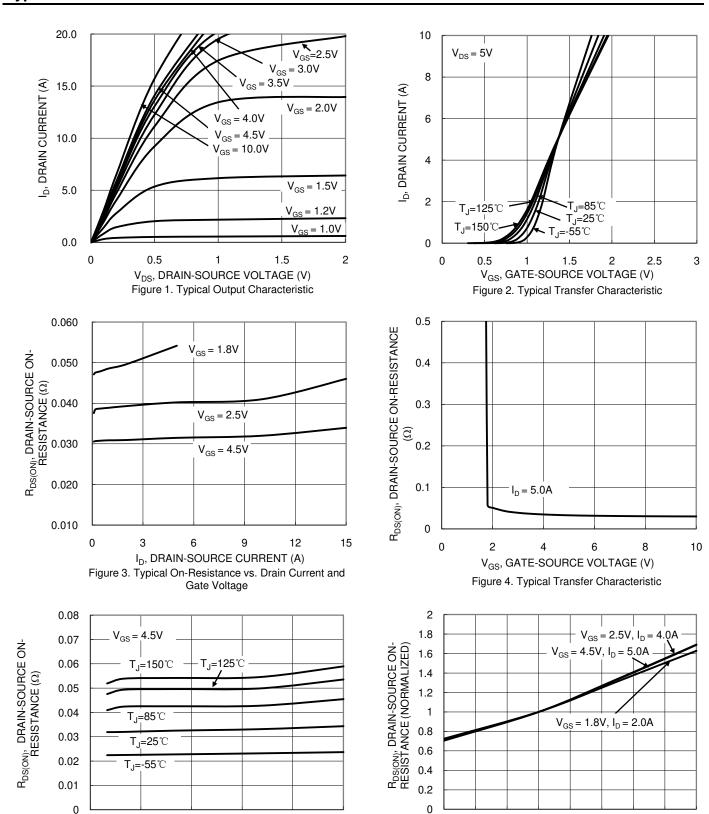


Figure 6. On-Resistance Variation with Temperature

50

 $T_J$ , JUNCTION TEMPERATURE ( $^{\circ}$ C)

75

100

3

6

9

I<sub>D</sub>, DRAIN CURRENT (A)
Figure 5. Typical On-Resistance vs. Drain Current and

Temperature

12

15

-50

-25

0

25

125



### Typical Characteristics - N-CHANNEL (Cont.)

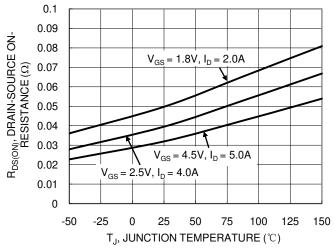
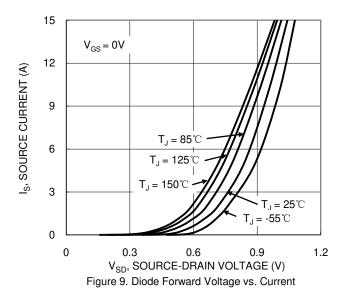
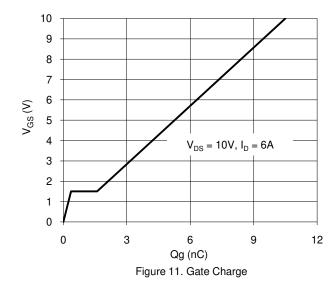


Figure 7. On-Resistance Variation with Temperature





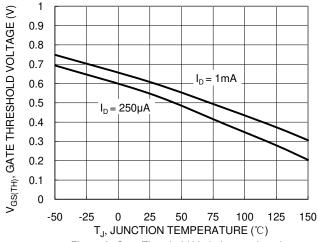
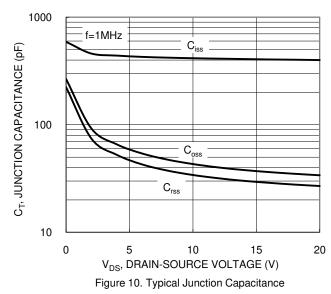
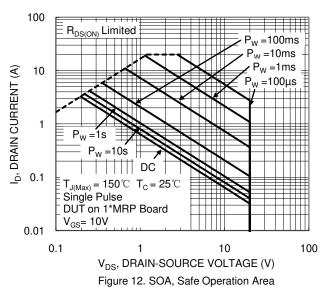


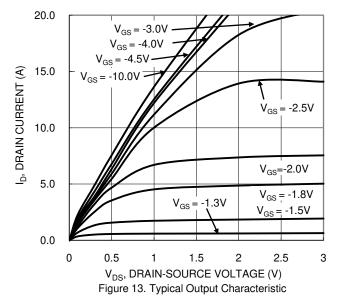
Figure 8. Gate Threshold Variation vs. Junction Temperature







## **Typical Characteristics - P-CHANNEL**



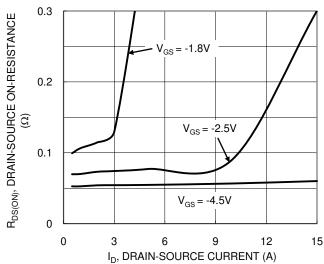


Figure 15. Typical On-Resistance vs. Drain Current and Gate Voltage

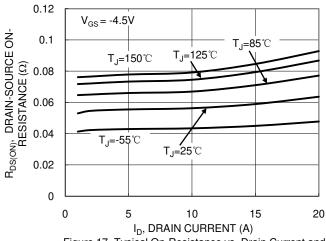
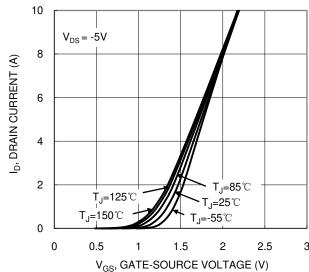


Figure 17. Typical On-Resistance vs. Drain Current and Junction Temperature



V<sub>GS</sub>, GATE-SOURCE VOLTAGE (V) Figure 14. Typical Transfer Characteristic

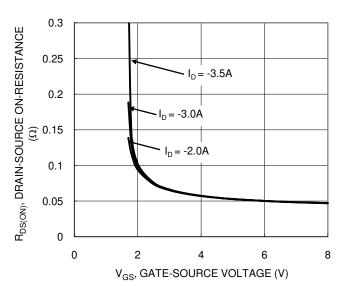


Figure 16. Typical Transfer Characteristic

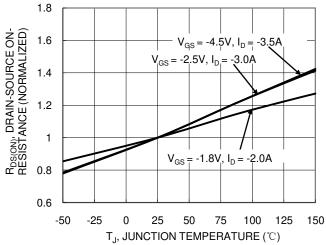
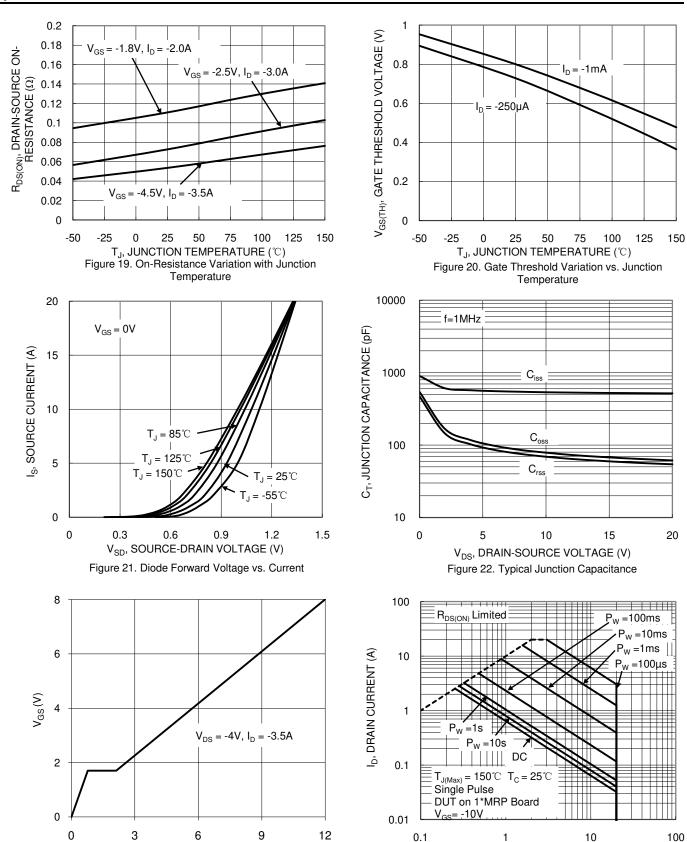


Figure 18. On-Resistance Variation with Junction Temperature



#### Typical Characteristics - P-CHANNEL (Cont.)



Qg (nC)

Figure 23. Gate Charge

V<sub>DS</sub>, DRAIN-SOURCE VOLTAGE (V)

Figure 24. SOA, Safe Operation Area



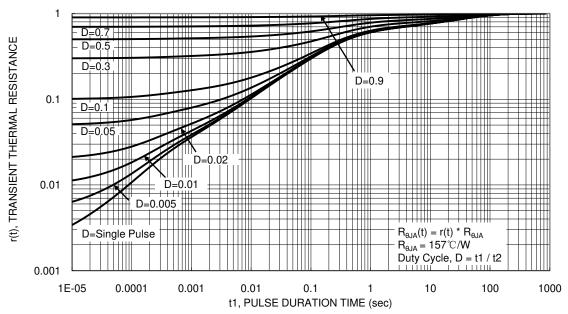
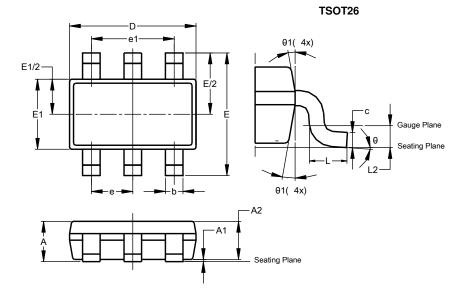


Figure 25. Transient Thermal Resistance



# **Package Outline Dimensions**

Please see http://www.diodes.com/package-outlines.html for the latest version.

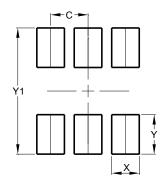


TSOT26								
Dim	Min	Max	Тур					
Α	-	1.00	-					
<b>A</b> 1	0.010	0.100	-					
A2	0.840	0.900	1					
D	2.800	3.000	2.900					
Е	2	2.800 BS	O					
E1	1.500	1.700	1.600					
b	0.300	0.450	1					
С	0.120	0.200	_					
e	0	0.950 BSC						
e1	1	.900 BS	С					
L	0.30	0.50	1					
L2	0.250 BSC							
θ	0°	8°	4°					
θ1	4°	12°	-					
Δ	II Dimen	sions in	mm					

# **Suggested Pad Layout**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### TSOT26



Dimensions	Value (in mm)
С	0.950
Х	0.700
Υ	1.000
Y1	3.199



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